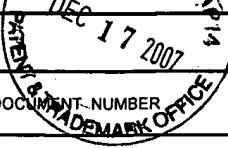


INFORMATION DISCLOSURE CITATION <small>(Use several sheets if necessary)</small>				ATTY DOCKET NO. TROLOGY 02.02	APPLICATION NO. 10/536,576			
				APPLICANT(S) Szwaykowski et al.				
				FILING DATE February 6, 2006	GROUP ART UNIT			
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